

AMENDMENTS TO THE SPECIFICATION

Please replace the Abstract with the following amended paragraph:

An apparatus for the on-chip testing of random access memory arrays. In representative embodiments, embedded circuitry ~~is disclosed which~~ provides the ability to test random access memory arrays on-chip ~~by means that do not required~~ without requiring substantial area on the chip. The circuits ~~disclosed~~ are inherently located closer to the tested area which reduces propagation delay errors. These advantages have been obtained by locating the circuitry necessary to perform such test in the addressing and input/output blocks of the RAM.